Development of Optimal Accelerated Life Test Plans for Weibull Distribution Under Intermittent Inspection⁺

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ABSTRACT

For Weibull distributed lifetimes, this paper presents asymptotically optimal accelerated life test plans for practical applications under intermittent inspection and type—I censoring. Computational results show that the asymptotic variance of a low quantile at the design stress as optimal criterion is insensitive to the number of inspections at overstress levels.

Sensitivity analyses indicate that optimal plans are robust enough to moderate departures of estimated failure probabilities at the design and high stresses as input parameters to plan accelerated life tests from their true values.

Monte Carlo simulation for small sample study on optimal accelerated life test plans developed by the asymptotic maximum likelihood theory is conducted. Simulation results suggest that optimal plans are satisfactory for sample size in practice.

1. Introduction

This paper considers an optimal design of accelerated life test(ALT) plans for Weibull distributed lifetimes on the assumption of intermittent inspection and type-I censoring.

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[·] 이 논문은 1988년도 문교부 지원 한국학술진홍재단의 자유공모과제 학술연구조성비에 의하며 연구되었음.

During the three preceding decades, Weibull distribution is probably the most popular model in the statistical analysis of failure time data(e, g, , see Lawless(1983)). This model provides a good description of many types of lifetimes, since its hazard function could be monotone decreasing, increasing or constant on the proper choice of the parameter values.

Accelerated life tests quickly furnish information about the life distribution at the design (use or normal) stress of high reliable products and materials. But further reduction in testing efforts and administrative advantages may by achieved by periodic inspection (a regular interval) or intermittent inspection in which test items are examined at certain points in time rather than continuous inspection.

Also, some failure data may be obtained only by repeated inspections of the products. For example, when an unit can not be monitored continuously such a cracked part inside machine as turbin wheel, the exact failure times can not be observed.

The resulting information called "grouped" or "interval" data by above inspection scheme consists of the number of failures in each interval and the number of units that survive until the censoring time.

Much works on the optimal ALT plans have been carried out under the assumption of continuous inspection and have chosen levels of some stresses and allocations to satisfy specified optimality criterion.

Developments in this area were contributed by Chernoff (1962), Little and Jebe (1969), Mann (1972), Meeker and Nelson (1976), Nelson and Keilpinski (1975), Nelson and Meeker (1978), Meeker (1984) and Meeker and Hahn (1985).

On the other hand, studies on statistical analysis of grouped data or design of the inspection scheme have been largely concerned with univariate sample from a single lifetime distribution by Kulldorff(1961), Ehrenfeld(1962), Nelson(1977), Archer(1982) and Meeker(1986).

As exception, Choi(1987) presented optimal ALT plans for exponential life distribution under equally spaced inspection scheme.

This paper provides ALT plans designed for widely applicable Weibull distribution by combining these interesting and important aspects of life tests, namely acceleration and intermittent inspection.

For type-I censoring, the method of maximum likelihood estimation in its asymptotic setting is the most universal and perhaps the only work instrument in hands of any applied statistician and engineer.

The optimality criterion adopted to develop optimal ALT plans is the asymptotic minimum variance of maximum likelihood estimator of a low quantile of the lifetime distribution at the design stress.

The decision variables, i.e., the low stress level, the proportion of test units to be allocated to the low and high stress are derived and computed with respect to parameters involved.

Sensitivity analyses are performed to asses the effect of misspecifying the unknown parameters on the optimal plans.

When dealing field data, there is a doubt whether sample size is large enough to provide a

reasonable accuracy of the asymptotic maximum likelihood theory and optimality of ALT plans

A Monte Carlo study on the small and moderate sample properties of maximum likelihood estimators for optimal ALT Plans is conducted and discussed.

2. The Model and Maximum Likelihood Estimation

The results in this article are based on the following assumption:

1) The lifetimes of test units are independently and identically distributed as Weibull, that is, the probability density function of lifetime T is given by

$$f(t) = \beta/\Theta(t/\Theta)^{\beta-1} \exp\{(-t/\Theta)^{\beta}\} \text{ for } t \ge 0, \beta, \theta > 0$$
 (2.1)

2) The scale parameter is

$$\Theta = \exp(B_0 + B_1 x) \tag{2.2}$$

where x is the (transformed) stress level.

- 3) The shape parameter β dose not depend on the level of stress.
- 4) The design stress level x_0 and high stress level x_2 are prespecified, while low stress level x_1 is to be optimally determined.
- 5) n_1 , n_2 units are tested independent of stress levels at the low and high stress simultaneously until some censoring time (Type-I censoring).
- 6) Inspections are conducted only at specified points $t_{i1}, t_{i2}, \dots, t_{iK_i}, i=1, 2, K_i \ge 2$ and let $t_{i0}=0$ and $t_{i,K_i+1}=\infty$.

Eq. (2.2) is well known simple linear regression model such as the power rule model or Arrhenius model at life stress relationship in ALT (see e.g., Lawless (1982), Chapter 6 and Mann et al. (1974), Chapter 9).

If product life T has a Weibull distribution, Y = In T has a smallest extreme value distribution that the distribution function is written as

$$F(y) = 1 - \exp\left[-\exp\{(y - \mu)/\sigma\}\right], \quad -\infty \langle y \langle \infty \rangle$$
 (2.3)

where $\sigma > 0$, $-\infty < \mu < \infty$, $\sigma = 1/\beta$, $\mu = \ln \Theta$

The number of test units allocated to x_1 and x_2 are respectively given by

$$n_1 = \pi N, \quad n_2 = (1 - \pi) N = N - n$$
 (2.4)

where N is total number of test units preassigned, and π is to be optimally determined.

Define m_{ij} =the number of units(at stress level x_i) failed in $[t_{i,j-1}, t_{ij}), j=1,2,\cdots, K_i+1$ P_{ij} =the probability of failure at stress level x_i in $[t_{i,j-1}, t_{ij}), j=1,2,\cdots, K_i+1$

Then the resulting grouped data $\{m_{ij}, i=1, 2, j=1, 2, \dots, K_i+1\}$ are used to estimate B_0, B_1 and σ and grouped data structure of intermittent inspection—can be described as in Figure 1.

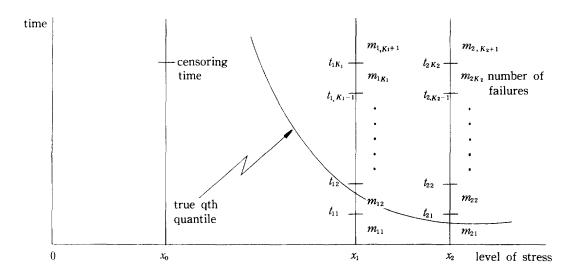


Figure 1. Grouped Data structure

A primary concern is to estimate the low q th quantile, y_q of extreme value distribution at the design stress as follow.

$$y_q = \ln t_q = B_0 + B_1 x + \sigma \ln \{-\ln(1-q)\}$$
 (2.5)

Let \hat{B}_0 , \hat{B}_1 and $\hat{\sigma}$ are maximum likelihood estimates of B_0 , B_1 and σ respectively, then estimate of $y_q(\hat{y}_q)$ is

$$\hat{y}_q = \hat{B}_0 + \hat{B}_1 x_0 + \sigma \ln\{(-\ln(1-q))\}$$
 (2.6)

The problem of designing the optimal ALT plan under intermittent inspection can be stated as given N, x_0 , x_2 , inspection schemes at x_1 and x_2 to determine π and x_1 such that large sample variance of \hat{y}_q is minimized.

At each stress, the grouped data $\{m_{ij}, j=1, 2, \dots, K_i+1\}$ are multinomially distributed with parameters n_i and $\{P_{ij}, j=1, 2, \dots, K_i+1\}$,

The likelihood function is given by

$$L = \prod_{i=1}^{2} L_{i} = \prod_{i=1}^{2} \prod_{j=1}^{K_{i+1}} n_{i} P_{ij}^{m_{ij}}(m_{ij})^{-1}$$
(2.7)

Then the log-likelihood function is

$$1(B_0, B_1, \sigma) = \sum_{i=1}^{2} \ln L_i$$

$$=C+\sum_{i=1}^{2}\sum_{j=1}^{R_{i+1}}m_{ij}\ln P_{ij}$$
 (2.8)

where C is constant and

$$P_{ij} = \exp\{-\exp(z_{i,j-1})\} - \exp\{-\exp(z_{ij})\}, \tag{2.9}$$

$$z_{ij} = (y_{ij} - B_0 - B_1 x_i) / \sigma$$
 for $i = 1, 2$ and $j = 0, 1, \dots, K_i + 1$ (2.10)

The three partial derivatives of log-likelihood function are

$$\frac{\partial 1}{\partial B_0} = \sigma^{-1} \sum_{i=1}^{2} \sum_{j=1}^{K_{i+1}} m_{ij} (A_i, j_{-1} - A_{ij}) / P_{ij}$$

$$\frac{\partial 1}{\partial B_1} = \sigma^{-1} \sum_{i=1}^{2} \sum_{j=1}^{K_{i+1}} x_i \ m_{ij} \ (A_i, _{j-1} - A_{ij}) / P_{ij}$$

$$\frac{\partial 1}{\partial \sigma} = \sigma^{-1} \sum_{i=1}^{2} \sum_{j=1}^{K_{i+1}} m_{ij} (D_{i,j-1} - D_{ij}) / P_{ij}$$
(2.11)

where $A_{ij} = \begin{cases} \exp \{z_{ij} - \exp(z_{ij})\}, & j = 2, \dots, K_i \\ 0, & j = 0, K_i + 1 \end{cases}$ (2.12)

$$D_{ij} = z_{ij}A_{ij} \tag{2.13}$$

when define $B_2 = \sigma$ temporarily, then the Fisher information matrix for the grouped data at each stress level has the following form (See Rao(1973)).

$$F_i = n_i (f_{gh}^{(i)})_{g, h=0, 1, 2}$$
 $i = 1, 2$

$$f_{\mathbf{g}h}^{(i)} = \sum_{j=1}^{K_{i+1}} \frac{\left(\frac{\partial P_{ij}}{\partial B_{\mathbf{g}}}\right) \left(\frac{\partial P_{ij}}{\partial B_{h}}\right)}{P_{ij}}$$
(2.14)

After some algebraric manipulation, I obtain

$$f_{00}^{(i)} = \sigma^{-2} \sum_{j=1}^{K_{i+1}} (A_i, j-1 - A_{ij})^2 / P_{ij}$$

$$f_{01}^{(i)} = x_i f_{00}^{(i)}$$

$$f_1^{(i)} = x_i^2 f_0^{(i)}$$

$$f_{02}^{(i)} = \sigma^{-2} \sum_{j=1}^{K_{i+1}} (A_{i, j-1} - A_{ij}) (D_{i, j-1} - D_{ij}) / P_{ij}$$

$$f_{12}^{(i)} = x_i f_{02}^{(i)}$$

$$f_{22}^{(i)} = \sigma^{-2} \sum_{i=1}^{K_{i+1}} (D_i, j-1 - D_{ij}) / P_{ij}$$
 (2.15)

The total Fisher information matrix for any plan with a sample of N independent observations is given by

$$F = \sum_{i=1}^{2} F_i = N\left(\pi f_{gh}^{(1)} + (1-\pi) f_{gh}^{(2)}\right) g, h = 0, 1, 2$$
(2.16)

By taking inverse of F, the asymptotic covariance matrix is obtained by

$$V = F^{-1} (2, 17)$$

Newton-Raphson method or scoring method may be appropriate and convenient for deriving maximum likelihood estimates of B_0 , B_1 , and σ . Burridge (1980) discussed conditions for regression model with grouped data that \log -likelihood is concave. Also, the existence and uniqueness of maximum likelihood estimates for Weibull grouped data at the design stress was given by Cheng and Chen(1988).

Further, the asymptotic variance of the estimator of the given q th quantile at x_0 is

Avar
$$\{\hat{y}_{\sigma}(x_0)\} = [1 \ x_0 \ Uq] \ F^{-1} \ [1 \ x_0 \ Uq]' \text{ where } Uq = \ln\{-\ln(1-q)\}$$
 (2.18)

where Avar denotes the asymptotic variance, and is a function of σ , B_0 , B_1 , q, π , N and x_i , i = 0, 1, 2.

3. Optimal Plans and Computational Results

An optimal ALT plan provides the asymptotic best estimate of the quantile at the design stress.

As a consequence in section 2, the optimal plan is to be determine optimal x_1 and $\pi(x_1^*, \pi^*)$ for the given values of B_0 , B_1 , q and prespecified inspection scheme to minimize standardized asymptotic variance as the follow.

$$\operatorname{Min}_{x_1, \pi} \left[\frac{N}{\sigma^2} \operatorname{Avar} \{ \hat{y}_q(x_0) \} \right] = V_q,_{k}$$
(3.1)

subject to $0 < \pi < 1$, $x_0 \le x_1 < x_2$

The constrained optimization problem can be avoided by simple transformation of variables to unconstrained problem, i.e., $v_1 = \ln\{(x_1 - x_0)/(x_2 - x_1)\}$ and $v_2 = \ln\{\pi/(1-\pi)\}$ and solved by the Powell's conjugate direction method (1964).

To develop optimal ALT plans, we set $t_{k_1} = t_{k_2} = t_c$, $K_1 = K_2 = k$. Further, the parameters are standardized such that let $t_c = 1$ and let range of new parameters for stress level [0, 1].

Under the above reparameterization, adjusted parameters (s, b_0, b_1) can be easily calculated by original parameters (x, B_0, B_1)

$$s = (x - x_0) / (x_2 - x_0)$$

$$b_1 = (x_2 - x_0) B_1$$

$$b_0 = B_0 + B_1 x - \ln t_c$$
(3. 2)

However, no generality is lost under the above standardization.

It is important that experimenters choose the inspection scheme for ALT plan. Though equally spaced inspection times are common at the high and low stress and are widely accepted by the ease of implementation, it is statistically inefficient in case of decreasing and constant failure rate and additional estimation of σ to design ALT plans must be needed.

Therefore, I take a choice the equal probability inspection scheme that is reasonably statistically efficient (Meeker (1986) gave guidelines for choosing statistically efficient inspection times and discussed the inspection scheme and Hassanein (1972) gave optimum inspection times with type—I censoring for a particular criterion from Weibull data).

Inputs required to develop an optimal plan are "guess" values for b_0 , b_1 and σ ,

In actual experiments, the following defined quantities can be used instead of b_0 , b_1 and σ by information of product design, or engineering judgement of preliminary test because of the convenience of estimation.

 P_d = probability that an unit fails in $[0, t_c)$ at the design stress

 P_h = probability that an unit fails in $[0, t_c)$ at the high stress

Then the corresponding standardized intercept and standardized slope can be determined as follows.

$$b_0/\sigma = -\ln\{-\ln(1 - P_d)\} + \ln t_c/\sigma \tag{3.3}$$

$$b_1/\sigma = -\ln\{-\ln(1-P_h)\} - b_0/\sigma + \ln t_c/\sigma$$
 (3.4)

Accordingly to P_d and P_h , the probability that an unit will fail at s_i is given by

$$P_t = 1 - \exp[-\exp\{z_{0k}(1 - s_1) + s_1 \ z_{2k}\}]$$
(3.5)

where $z_{ik} = \{\ln t_c - (b_0 + b_1 s_i)\}/\sigma$ for i = 0, 2 can be determined by Eqs. (3.3) and (3.4). Hence inspection times $\{t_{i1}, \dots, t_{ik}; i = 1, 2\}$ can be calculated by Eqs. (3.5) and (3.6).

$$y_{ij}/\sigma = \ln t_{ij}/\sigma = (b_0 + b_1 s_i)/\sigma + \ln\{-\ln(1 - jP_i/k)\}$$
(3.6)

where $P_1 = P_t$ and $P_2 = P_h$

While inputs to design optimal ALT plans are only P_d and P_h under equal probability inspection scheme, additional estimate of σ or β is needed to determine inspection times at each stress level.

Partial listings of optimal ALT plans that are summarized by Tables 1-2 and these tables provide for the combinations of

$$k = 2, 3, 5, 10, \infty$$

$$P_d = 0.0001, 0.001, 0.01, 0.05, 0.1$$

$$P_h = 0.1, 0.25, 0.05, 0.7, 0.9, 0.99$$

$$q = 0.01, 0.1$$

subject to
$$P_d \le q < P_h$$
 (3.7)

To limit the derived extrapolation incurred in implementation of ALT plans, Eq. (3.7) is assigned.

The tabulations show standardized intercept and slope of location parameter $(b_0/\sigma \text{ and } b_{1\ell}\sigma)$, optimal level of low stress (s_i^*) , optimal proportion allocated to low stress (π^*) , standardized asymptotic minimum variance (V_q, k) ratio of V_q , to continuous inspection $(V_q, k/V_q, \infty)$, and probability of failure until t_c at $s_1(P_t)$.

Table 1. Optimal ALT Plans for Weibull Grouped Data Under Equal Probability Inspection Scheme (q=0, 01)

P_a	P_h	b_0/σ	b_1/σ	k	S ₁ *	π*	$V_{q, k}$	ratio ^{\$}	P_t	P_d	P_h	b_0/σ	b_1/σ	k s	* π*	$V_{q, \star}$	ratio	P_t
:000;			-10.7375		.7248		130.7717		.2133	.0010	.5000	6.9073	-6.5407	2 .64	30 .7425	234.7117	1.1351	.0649
.0001			-10.7375		.7250		123.2560		.2137	.0010			-6.5407		52 .7636	220.5429	1.0666	.0618
.0061			-10.7375		.7260		119.4980		.2157	.0010	.5000	6.9073	-6.5407			213.4583	1.0323	.0600
.9001			-10.7375		.7267		117.6098		.2172	.0010			-6.5407			209.6367		.0589
10(8)	.9900	9.2103	-10.7375	00	.7268	.7344	116.5619	1.0000	.2172	.0010	.5000	6.9073	-6.5407	oo .62	51 .7 87 0	206.7750	1.0000	.0580
.0001			-10.0443		.7505	.6878	210.8054	1.1492	. 1712	.0010	.2500	6.9073	-5.6614	2 .60	96 .7267	435.8113	1.1698	.0311
.0001			-10.0443		.7449		196,1689		. 1627	.0010				3 .60	.7512	404.8491	1.0867	.0295
.0001			-10.0443		.7417		189.2252		.1580				-5.6614		.7651	388.7536	1.0435	.0286
.0001			-10.0443		.7397		185.7367		.1552	.0010	2500	6.9073	-5.6614	10 .59	14 .7734	379,7031	1.0192	.0281
10001	.9000	9,2103	-10.0443	(30)	.7380	.7354	183.4289	1.0000	. 1528	.0010	.2500	6.9073	-5.6614	00 .58	34 .7802	372,5376	1.0000	.0276
.0001	.7000	9.2103	-9.3959	2	.752 8	.6775	348.0181	1.1876	.1113	.0010	.1000	6.9073	-4.6569	2 .55	1 .7000	872.2240	1.2188	.0129
.0001	7000	9.2103	-9.3959	3	.7467	.7036	319.5947	1.0906	. 1054				-4.6569		7288 .7	797.0359	1.1137	.0123
.0001	.7000	9.2103	-9.3959	5	.7427	.7181	305.6709	1.0431	.1018	.0010	.1000	6.9073	-4.6569	5 ,53	32 .7459	757.1734	1.0580	.0119
.0001			-9.3959		.7403		298.3375		.0996	.0010	.1000	6.9073	-4.6569	10 .52	.7561	734.2798	1.0260	.0117
.0001	.7000	9.2103	-9.3959	00	.7384	7326	293.0518	1.0000	.0980	,0010	.1000	6.9073	-4.6569	00 .52	.7651	715.6390	1.0000	.0115
.0001	.5000	9.2103	-8.8438	2	.7486	.6679	538.6126	1.2101	.0723	.0100	.9900	4.6001	-6.1273	2 .42	37 .7976	39.5213	1,2029	. 1261
.0001	.5000	9.2103	-8.8438	3	.7415	.6956	491.5312	1.1043	.0680	.0100	.9900	4.6001	-6.1273	3 .44	.8065	36.5945	1.1138	.1427
,000!	.5000	3.2103	-8.8438	5	.7375	.7113	467.7861	1.0510	.0657	.0100	.9900	4.6001	-6.1273			34.6938	1.0559	.1546
.0001	.5000	9.2100	-8.8438	10	.7349	.7206	454.8605	1.0220	.0643	.0100	.9900	4,6001	-6.1273	10 .46	9 ,8184	33.5639	1.0215	.1620
.0001	.5000	3.2103	-8.8438	00	.7329	.7279	445.0875	1.0000	.0632	.0100	.9900	4.6001	-6.1273	œ .47	.8216	32.8552	1.0000	.1667
.9001	.2500	9.2103	-7.9644	2	.7320	.6508	1090.1309	1.2390	.0335	.0100	.9000	4.6001	-5.4342	2 .45	9 .8488	42.2730	1.0288	.1105
.0001	.2500	9.2103	-7.9644	3	.7250	.6803	987.2476	1.1221	.0317	.0100	.9000	4.6001	-5.4342			41.7564	1.0161	.1129
.0001	.2500	9.2103	-7.9644	5	.7208	.6975	933.7790	1.0613	.0306	.0100			-5.4342			41.4027		1145
.0001	.2500	9.2103	-7.3644	10	.7182	.7081	903.6893	1.0271	.0300	.0100			-5.4342			41.2063		.1153
.0001	.2500	9.2103	-7.3644	00	.7159	.7169	979.8471	1.0000	.0295	.0100			-5.4342		9 .8541	41.0949		.1157
.0001	.1000	9.2103	-6.9599	2	.7033	.6259	2451.6696	1.2754	.0133	.0100	.7000	4,6001	-4.7858	2 .42	2 .8770	53.4733	1.0050	.0727
					.6970		2196.4671		.0127	.0100			-4.7858			53.3540		0730
					.6921		2061.8967		.0123	.0100			-4.7858			53.2772		.0732
			-6.3599		.6892		1984.8728		.0120	.0100			-4.7858			53.2344		.0733
.0001	.1000	9.2103	-6.9599	00	.6866		1922.3297		.0118	.0100			-4.7858			53.2061		.0734
.0010	.9900	6.9073	-8.4344	2	.6192	.7571	71.2079	1.0996	. 1694	.0100	.5000	4.6001	-4,2336	2 .36	2 .8986	66.6149	1.0012	.0464
			-8.4344		6251	7692	68.0276		.1771				-4.2336			66.5786		.0465
.0010	.9900	6.9073	-8.4344	5	.6301	.7752	66.2282	1.0227	.1840	.0100	.5000	4.6001	-4.2336			66.5557	1.0003	.0465
.0010	.9900	5.9073	-8.4344	10	.6333	.7784	65,2604	1.0078	.1886	.0100	.5000	4.6001	-4.2336			66.5429	1.0001	.0466
.0010	.9900	6,9073	-8.4344	00	.6350	.7802	64.7585	1.0000	.1910	.0100	.5000	4.6001	-4.2336	no .36'			1.0000	.0466
.0010	.9000	6.9073	-7.7413	2	.6548	.7557	103.0296	1.0824	.1471	.0100	.2500	4.6001	-3.3542	2 .22	5 ,9394	89,3754	1.0001	.0210
			-7.7413		.6499	.7718			.1420				-3.3542			89.3702		.0210
.0010			-7.7413		6473	.7799	96.7250		.1394	.0100			-3.3542			89.3672		.0210
			-7.7413		.6 45 8	.7840	95.7637		.1379				-3.3542			89.3658		.0210
.0010			-7.7413		,6444	.7868	95.1885		.1366				-3.3542				1.0000	
.0010	.7000	6,9073	-7.0929	2	.6548	,7497	159.4616	1.1121	.0989	.0100	.1000	4,6001	-2.3498	2 .00	0 1.0000	100.0537	1.0000	.0100
			-7.0929		.6477		151.0123		.0942	.0100			-2.3498		0 1.0000	100.0537		.0100
			-7.0929		6435		146.9501		.0916				-2.3498		0 1.0000	100.0537		.0100
			-7.0929		.6410		144.8545		.0900				-2.3498		0 1.0000	100.0536		.0100
			-7.0929		.6390		143.3829		.0888	.0100			-2.3498			100.0535		.0100
															- 1,0000	10070000	1,,,,,,,	

 $[\]phi$) ratio = $V_{\bar{q}}$, $\kappa/V_{\bar{q}}$,

Table 2. Optimal ALT Plans for Weibull Grouped Data Under Equal Probability Inspection Scheme (q=0,1)

P_d	P_h	b ₀/σ	b_1/σ	k	s: *	π•	$V_{q, k}$	ratio	P_{ι}	P _d	$P_{\mathbf{h}}$	b_u/σ	b_1/σ	k	s_i^{\bullet}	π*	$V_{q, k}$	ratio	F
0001	.9900	3.2103	-10.7375	2	.7623	6246	163.6684	1.1937	.3016	.0100	.7000	4.6001	-4.7858	2	.5412	.6987	86,7961	1.2187	.12
0001	.3900	9.2103	-10.7375	9	.7572	.6514	149.6630	1.0915	.2879	.0100	.7000	4.6001	-4.7858	ŝ	.5288	.7282	78,9348	1.1084	.11
0001			-10.7375		.7541		142.8650	1.0419	.2799				-4.7858		.5210	.7448	74.9724		.11
1001			-10.7375		.7522		139,4049		.2752				-4.7858		.5160	7546	72.8239		-11
1001	.9900	9.2103	-10.7375	œ	.7502	.6799	137.1146	1,0000	.2703	.0100	.7000	4.6001	-4.7858	30	.5118	.7624	71.2179	1.0000	.10
1001	.9000	9.2103	-10.0443	2	.7737	.6104			.2111	.0100			-4.2336		.5079	.6786	123,2949		.08
1001			-10.0443		.7670	.6407			.1989	.0100				3	.4962	.7110	110.8267		.0
100			-10.0443		.7627	.6578			.1913	.0100			-4.2336		.4880	7299	104.3942		.0
001 001			-10.0443 -16.0443		.7599 .7576		227.1697 221.8382	1.0240	.1866 .1827	.0100			-4.2336 -4.2336		.4827 .4777	.7411 .7507	100.8141 98.0369		.0
WI	1,340,00	9-4190	-10:0449	v	11910	.0/31	1+900¢	110000	1051	.0100	13000	1,000]	71.2330		19141	1 FOUT	30,4903	1,1000	.0
		9.2103	-9.3959		.7719	.6938			.1316	.0100			-3.3542		.4248		213.3770		.0
100		9.2100	-9.2953	0	.7654		413.9690	1.1481	.1243	.0100			-3.3542		.4125	.6723		1.1679	Ĵ.
001		9.2102	-9.3959		.7611	6469		1.0715	.1198	.0100			-3.3542		,4043 2005		174,7893		.0
001 001		9.2103	-9.3959 -9.3959		.7584 .7561	.6583 .6675		1.0304	.1170 .1146				-3.3542 -3.3542		.3992		167.1865 161.0681		.0.
N/I		3.4100	-5.4332	.,,	1100	.0914	23119093	110000	11110	,0100	. 2000	1.0001	-0.0045	0)	10041	. (631	101.0001	11:0000	
001		9.2107	-8.8438		.7650	.5807		1.3252	.0831	1			-4.4974		.3098	.8540	15.5244		.1
100		9.2103	-8.8438		.7589	.6155		1.1628	.0789	.0500			-4.4974		.3147	.8528	15.1038		J.
01		9.2103	-8.8438		.7548 2500	.6361			.0762				-4.4974		.3196	-8671	14.8747 14.7524		.1
XO1 XO1		9.2100	-8. 843 8 -8. 843 8		.7522 .7494		574.4751 555.1706		.0745 .0728	.0500			-4.4974 -4.4974		.3230	.8692 .8709	14.6858		. !
•														-			71.0000	110001	
61		9,2107	-7.3644		.7481			1.3547	.0380	.0500			-3.8042	-	.3162	8546	19.4684		
01			-7.9644		.7422			1.1814	.0362	.0500			-3.8042		.3063	8682	18.8325		
01			-7.9644		.7382		1226.7136	1.0913	.0351	.0500			-3.8042		.3004	8754	18.5218		
01			-7.3644		."355 2004		1169.5452	1.0405	.0344	.0500			-3.8042		.2964	.8794	18.3611		
01	.2000	9.2103	-7.9644	ď:	.7335	,6415	1124 0687	1.0000	.0338	, 05(X)	.9000	2.9702	-3.8042	œ	.2928	.8825	18.2500	1,0000	•
10			-3,4344	2	.6882	.659€	89.5749	1.1666	.2825	.0500	.7000	2.9702	-3.1558	2	.2662	8542	24.6959	1.107€	
10	.3900	6.9073	-8,4344	2	.6829	.6851	82,8185	1.078€	.2721	.0500	.7000	2.9702	-3.1558	3	.2515	8724	23.5071	1.0540	
10	.3900	6.9095	-8,4344	£	.6800	.6989	79,5338	1.0358	.2664	.0500	.7000	2.9702	-3.1558	5	.2419	8825	22.8960	1.0269	
10	. 3900	6.9070	-x .4344	10	.6782	.7065	77.8674	1.0141	.2629	.0500	.7000	2.9702	-2.1558	10	2358	.8883	22.5578	1.011"	
10	.9900	6,9070	-8.4344	Œι	.5761	.7118	76.7830	1.0000	.2591	.0530	.7000	2.9702	÷3.1558	99	.2303	.8933	22.2973	1.0000	.1
10	.2000	€.9073	-7.7413	2	.7019	6143	147.1947	1.2271	.2047	.0500	.5000	2.9702	-2.6037	2	.1951	.8504	29,5953	1.1506	. (
10	.3000	6,9023	-7.7413	ŝ	.6934	.5736	133.0561	1.1093	.1930	.0500	.5000	2,9702	-2.6037	j	.1786	8736	27.7353	1.0783	į.
10	.9000	6.3013	-7,7413	5	.6881	.5898	126.1297	1.0515	.1860	.0500	.5000	2.9702	-2.6037	5	.167?	.8869	26.7454	1.0398	
10	.3000	6.90%	-7,7413	10	6848	.6991	122,5065	1.0213	.1818	.050C	.5000	2.9702	-2.6037	19	.1609	8950	26.1779	1.0173	ď
10	.300	0.0000	-7.7413	OT.	.6821	.7061	119,9507	1.0000	.1784	.0500	.5000	2.9702	-2.6037	30	1545	.9019	25.7209	1.0000	1.
16	.0000	6,90%	-7,0929	9	6959	.6257	240.0574	1.2758	.1300	.0506	25(X)	2.9702	-1.7243	9	.0000	.8196	36,7528	1.9405	.(
10		6.90%	-7.0929		.6871	6582		1.1357	.1226	.0500			-1.7243		.0000	8592	33.4040		
10		6,9078	-1.0929		.6810	.6773	200.5237	1.0657	.1178	.0500			-1.7243		.0000	.8834		1.0660	j
10		5,9073	-7.0929		.6774	.6883	193,4246	1.0280	.1150	.0500			-1.7243		.0000	8988	30.5147	1.0300	į
10	7000	6,9073	-7.0929	20	.67£]	.6968	188,1619	1.0000	.1133	.0500	.2500	2.9702	-1.7243	00)	.0000	.9124	29.6273	1.0000	,(
IC.	.5000	6.9670	-6.5407	2	.6824	.6093	365.6027	1.3050	.0832	1600	.9900	2.2504	-3.7775	2	.0871	.9598	ñ ekke	1.6391	
u. C		6.9073	-6.5407	6	.6741	.6436	323.0686	1.1532	.0832	1000		2.2504	-3.7775	3	.1125	.9513		1.0229	
иь 110		6.3072	-5.5407		.6679	.6640	301,3474	1.0757	.0759	1000		2.2564	-3.7775	5	.1307	.9458		1.0123	
10 10		6.3073	-6.5407		.6650	.6759	289.2592		.0746	1000		2.2504	-3.7775	-	.1419	.9427		1.0048	
			-6.5407		.66:9		280.1508		.0731	.1000		2.2504	-3.7775		.1489	.9408		1,0000	
• 6	orne	p 3091	£ 2004 x	n	gant	Eave	710 0000	1 2400	1990	Topo	Oran	g genu	.s 6011	1	0405	() () () ()	g arte	. pase	
10 10		6,90%	-5.6614 -5.6614		. 6495 . 3498	.6156	719.2338 629.0110		.0388			2.2504 2.2504	-3.0844 -3.0844		.0463 .0520	.9827 .9811		1.0028	
10 10		6,300	-5.6614		5358	.6378			.0359			2.2504	-3.0844		.0554	.9801		1,0006	
iic iic			-5.6614		.6318		555.259C		.0352				-3.0844		.0570	.3797		1,0001	
			-5.6614		.6282		535,9912		.0345				-3.0844		.0576	.9795		1,0000	
			-6.1273		.5435	.7324	38.0512		.2448				-2.4360			1.0000		1.0002	
			-6.1273		,5405	.7530	35.9359		.2416			2.2504	-2.4360			1.0000		1.0002	
00			-€.1270 € 1000		.5291 econ	.7644	34,8959		.2392				-2,4360 -2,4360			1.0000	10,0088		.1
100 100			-6.1273 -6.1273		.5363 .5368	.7704 .7746	34.3695 34.0438		.2382 .2363				-2.4360 -2.4360			1.0000		1,0001	
w	. 240)	T (*1652)	911 <u>5</u> 10	**	19/1/12		0:,0149	,10000	(500)	17000	11000	U-2001	p. 1000		1000	a naryury	10.19013	; 1,0000	
			-5.4342		5598	.7182	57.4116		.1899										
			-5.4342		5483	7436	53.1568			1									
			-5.4342		.5423	.7571	51.069?			1									
			-5.4342		.5381	.7649	49.9785												
	3000	4.6001	-5.4342	00	.5344	.7709	49.2094	1.0000	.1675	1									

Optimal ALT plans under continuous inspection are determined by results of Meeker and Nelson (1976), Nelson and Meeker (1978) and Escobar and Meeker (1986).

General conclusions may be drawn from the tables.

(1) One of main conclusion is that V_q , k is not sensitive to k and this insensitivity becomes more apparent as q decreases and $k \ge 3$.

This implies that in designing ALT plans under intermittent inspection for estimating a low quantile at the design stress, the large number of inspections must be not necessarily, which is a reason that experimenters choose intermittent inspection rather than continuous inspection by reducing inspection cost and testing efforts.

- (2) A striking phenomenon is that the optimal stress level(s_i^*) and the optimal proportion of test units allocated to the low stress(π^*) are rather stable over $k \ge 3$ for all cases considered.
- (3) Incidently as quantile is close to P_d and $P_h \le 0.9$, π^* is more stable. As P_d increase and/ or P_h decreases, s_1^* gets close to the design stress level and π^* increases for all quantiles. In particular, when $q \approx P_d$ and $P_h \le 10 \cdot P_d$, $s_1^* \approx 0$ and $\pi^* \approx 1$, which almost no need for an ALT.
- (4) As number of inspections increase, π^* doesn't decrease and s_1^* almost nondecreases so that information of test results at the low stress can be gained a little more when $q > P_d$.

EXAMPLE

Meeker and Hahn(1985) gave data for an adhesive—bonded power element in an ALT that estimated the relationship between failure time and temperature.

In this example, 300 items were available for testing between 50°C and 120°C. Censoring time was 6 months and it was anticipated that probability of failure at 50°C and 120°C would be about 0.1% and 90%.

Tenth percentile at the design stress (50°C) need to be estimated with three inspections. For example, $s_1^*=0.6868$ and $\pi^*=0.6715$ from Table 2. Thus,

$$x_1^* = (120 - 50) s_1^* + 50 = 98^{\circ}C$$

$$B_1/\sigma = \frac{-7.7413}{(120-50)} = -0.1106$$

$$B_0/\sigma = (6.9073 - 0.1106) + \ln 180 = 25.499$$

$$n_1 = 300 \cdot 0.6715 \approx 201$$

$$n_2 = 99$$

Inspection times at the high and low stresses can be determined by P_h , P_t , in Table 2, Eqs.

(3,5) and (3,6) and σ which may be estimated by graphical methods such as hazard, or probability plots or techniques described in Mann et al. (1974), chapter 5 using preliminary test at any overstress as the high stress etc. and historical data.

4. Sensitivity Analysis and Small Sample Study

To determine an optimal ALT plan, required inputs are guessed values for failure probability P_d and P_h until censoring time at the design and high stresses on behalf of unknown b_0 , b_1 and σ

Chernoff(1962) called this situation "locally optimal" and recommended sensitivity analysis. Let \tilde{P}_d and \tilde{P}_h be the guessed values of P_d and P_h respectively. For \tilde{P}_d and \tilde{P}_h , false optimal \tilde{s}_1^* and $\tilde{\pi}^*$ can be determined as s_1^* , π^* .

In Table 3-5, V_q , $_k(\tilde{s_1^*}, \ \tilde{\pi}^*)/V_q$, $_k(s_1^*, \ \pi^*)$ to asses the sensitivity of the test plans are listed for various cases of true P_a , P_h with k=3, q=0.01, 0.1 and k=10, q=0.1. This sensitivity means the relative amount of increase in V_q , $_k$ due to uncertainties involved in P_d and P_h .

From Table 3-5, I make an observation that moderate deviations from P_d and P_h (approximately $-70 \sim +200\%$ from P_d and $-10 \sim +30\%$ from P_h) are appreciably tolerable in terms of the asymptotic variance of a quantile at the design stress in sense that results of sensitivity is mostly not greater than 15%, although the detailed tabulations are not given here by limitation of space.

Table 4 and 5 show that the sensitivity values are fairly stable over number of inspection for given P_d and P_h .

Values of ratio less than 1 in Tables can be occurred because inspection times at two stress levels determined by P_d and P_h are different from them by \tilde{P}_d and \tilde{P}_h and these times by true P_d and P_h are not optimal inspection times to minimize V_q , v_h in the design of ALT plans.

It is a matter of great practical interest to asses the property of optimal ALT plans obtained using the method of maximum likelihood and asymptotic variance of the estimator.

true P_h	0.7	0, 8	0, 9	0.95	0. 99
0.003	1,0843	1, 1112	1.1374	1.1436	1, 1027
0.005	1.0209	1.0341	1.0446	1.0416	0.9964
0.01	1,0075	1,0027	1,0000	0.9962	0.9700
0.02	1.0448	1.0352	1.0352	1.0373	1,0462
0.03	1,0824	1.0774	1,0896	1, 1091	1, 1253

Table 3. Sensitivities of V_q , k when false $P_d=0.01$, false $P_h=0.9$, k=3 and q=0.01

Table 4. Sensitivities of V_q , k when false $P_d = 0.01$, false $P_h = 0.9$, k = 3 and q = 0.1

true P_h	0.7	0.8	0.9	0.95	0.99
0,003	1,0191	1.0437	1.0843	1, 1229	1, 2031
0,005	0.9868	1,0035	1.0316	1,0576	1, 1058
0.01	0.9803	0.9864	1,0000	1.0131	1.0340
0,02	1,0556	1.0481	1.0483	1,0539	1, 0689
0.03	1, 1770	1. 1554	1, 1469	1.1446	1, 1671

Table 5. Sensitivities of $V_{q,-k}$ when false $P_{\rm d}=0.01$, false $P_{\rm h}=0.9$, k=10 and q=0.1

true P_h	0.7	0.8	0.9	0, 95	0.99
0,003	1.0476	1, 0631	1.0842	1,0997	1, 1193
0,005	1.0100	1,0187	1.0311	1,0399	1.0489
0.01	0 . 998 9	0.9980	1,0000	1,0023	1,0048
0.02	1.0712	1.0566	1.0469	1.0447	1, 0493
0.03	1, 1892	1, 1594	1. 1378	1, 1316	1, 1387

Especially, when deal with field data, size of sample is often small or moderate. Thus whether small or moderate size of sample is applied to optimal ALT plans by large sample criterion, Monte Carlo study has been conducted.

The sample and parameter values included in this study is outlined in Table 6.

Analyses are based on 1000 replications for each of configurations. All data generation, parameter estimation and analyses are carry out using FORTRAN program and it is available from the author.

Table 6. Monte Carlo Configuration

P_d	P_h	k	quantile	sample size
0, 01	0.9	3	0, 01, 0, 1	40, 100, 200
0.01	0.9	5, ∞	0.1	40, 100, 200
0.01*	0.9	3	0.1	40, 100, 200

^{*)} a standard plan of the mid-low stress level, equal sample size at two stresses under equally spaced inspection scheme.

The quality of maximum likelihood estimates by optimal design of ALT has been measured by sample average, sample standard deviation, T - statistic, mean squared error (MSE) for b_0 , b_1 , σ and quantiles at the design stress,

The corresponding formulas related to b_0 are:

$$\bar{b}_{0} = \sum_{j=1}^{r} \hat{b}_{0}^{(j)} / r,$$

$$sd(b_{0}) = \sum_{j=1}^{r} (\hat{b}_{0}^{(j)} - \bar{b}_{0})^{2} / r$$

$$T(b_{0}) = \sqrt{r} (\bar{b}_{0} - b_{0}) / sd(b_{0})$$

$$MSE(b_{0}) = (\bar{b}_{0} - b_{0})^{2} + \{sd(b_{0})\}^{2}$$
(4, 1)

r: number of replications that converge by scoring method $\hat{b}_0^{(j)}$: estimate of b_0 at j th replication.

In similar way, those values for other parameters can be computed. Monte Carlo results are summarized in Table 7 for estimates of b_0 , b_1 , σ and some quantiles at the design stress,

I draw some conclusions on properties of optimal ALT plans developed by large sample criterion for small and moderate size of sample.

- (1) For moderate sample size (N=100, 200), optimal ALT plans produce overall satisfactory estimation of parameters. However, for small sample size (N=40), the estimates produce the substantially large biases and mean squared errors.
- (2) Results show that estimates of b_0 and quantiles at the design stress are almost positively biased and estimates of b_1 and σ are almost negatively biased.
 - (3) The increase of a sample size has a strong favorable effect on the quality of estimates.
- (4) Finally, simulation results show that major contribution of the mean squared error is due to the sample variance.

Table 8 contains results from comparision of estimates of 0.1th quantile at the design stress by optimal ALT plans (k=3, 5, ∞) and a standard plan(k=3), assuming that $\sigma=1$, with mid-dow stress level ($\gamma=0.5$) and equal sample size at two stress levels under equally spaced inspection scheme.

Inspection of Table 8 indicates that large sample criterion can be applied to moderate size of sample and estimates of 0.1th quantile at the design stress are a little positively skewed for all plans. The usefulness of large sample approximation can be checked by comparing sample standard deviation with asymptotic values, i.e., differences are 10% low under optimal ALT plans with k=3,5.

It appears that scoring method is quite satisfactory for censored data, but it may be necessary to replace it Newton-Raphson method with concave reparameterization by Burridge(1980) for grouped data owing to lower proportion of convergence by scoring method when number of

inspections are small.

Also, optimal ALT plans are better than a standard plan and plans with small number of inspections can be comparable with plans under continuous inspection. But for small sample size, optimal ALT plans with k=3, 5, ∞ are resulted in a poor quality of estimates.

5. Conclusion

In this paper, asymptotically optimal accelerated life test plans for Weibull distributed lifetimes under type—I censoring and intermittent inspection whose advantages lie in the simplicity obtained in the collection and handling of the data are developed for various cases to be applied practically in field.

Table 7. Monte Carlo Results by Optimal ALT Plans with $P_d\!=\!$ 0.01, $P_h\!=\!$ 0.9 and k= 3

para- meter	1 - 1	true para- meter/σ		sample mean / σ	sample std. deviation $/\sigma$	T – statistic	MSE /σ²	para- meter	quan- tile	true para – meter/σ	sam- ple size	sam- ple mean / σ	sample std, deviation / σ	T − statistic	MSE /σ²
			40	4.8897	2.5736	3.1897	6.7073			1	40	1.0197	0.5069	1.0435	9,2575
	0.01	4,6001	100	4.6394	1.2145	0.9457	1.4765		0.01		100	0.9898	0.2448	- 1,2185	9,0606
			200	4.6453	0.8571	1.5184).1367				200	0.9952	0.1724	- 6.7993	0.0298
<i>b</i> ₀			40	4.8530	1.9689	3.6555	3.9406	σ			40	1.0190	v.3764	1.4384	0.1421
	0.]	4.6001	100	4,6500	0.9960	1.4213	0.9945		0.1	!	100	0.3938	0.1834	- 0.3558	0,033*
			200	4.6443	0.7257	1.7694	0.5286				200	0.9997	0.1246	- 0.0593	0.0155
			40	- 5,7973	2.7505	- 3.7293	7.7524		0.01	C	40	0.2037	1.2235	4.7209	1.5383
	0.01	-5.4342	100	- 5.5133	1.4032	- 1.6509	1.9751				100	0.0861	0.7077	3.5621	0.5082
			200	- 5.4962	0.9656	- 1.8500	0.9363				200	0.0671	0.5119	3.7807	0.2666
b_1			40	- 5.7306	2.1070	- 4.0044	4.5273	Уq		2.3498	40	2.5599	1,4080	4.2465	2.0265
	0.1	-5.4342	190	- 5.4999	1.1094	- 1.6832	1.2352		0.1		100	2.4135	0.7559	2.3947	0.5754
			200	- 5,4774	0.8004	- 1.5501	0.6426				200	2,3951	0.5650	2.30 2 0	0.3213

^{*)} the quantile at the design stress level estimated by an optimal ALT plan

Table 8. Comparision of the Estimates of 0.1th Quantile at the Design Stress by Some ALT Plans with $P_d = 0.01$, $P_h = 0.9$ and True Parameter = 2.3498 σ

plan	sample size	sample mean / σ	sample std. deviation / o	T – statistic /σ	MSE /σ²	asymptotic standard deviation / σ
optimal ALT plan	40	2.5599	1,4080	4.2465	2.0265	1.1528
under equal probability	100	2.4135	0.7559	2.3947	ó.5754	0.7291
inspection ($k = 3$)	200	2,3951	0.5650	2.3020	0.3213	0.5155
optimal ALT plan	40	2.6558	1,4694	6.0674	2.2528	1.1299
under equal probability	100	2.4647	0.7795	4.3172	0.6209	0.7146
inspection ($k = 5$)	200	2.4087	0.5183	2.3654	0.2721	0.5052
optimal ALT plan	40	2.4726	1.5072	2.4465	2.4712	1.1092
under continuous	100	2.4287	0.7311	3.3621	0.5408	0.7015
inspection	200	2.3802	6.4908	1.9379	0.2418	0.4960
*a standard	40	2.6414	1.7474	4.4188	3.1385	1.3361
plan under	100	2.4718	0.9494	3,4693	0.9162	0.3450
equally spaced inspection $(k=3)$	200	2.3844	0.5759	1.6153	0.0029	0.5975

^{*)} an ALT plan tested at a mid-low stress and high stress levels with equal sample sizes assuming that $\sigma = 1$

Computational results indicate that the large number of inspections at overstress levels are not necessary and effect of guess estimates for parameters would expect to be fairly tolerable for range of parameter values considered.

Results for small sample study on optimal plans using large sample criterion show that the effect of large sample approximation is not substantial for moderate size of sample, but is considerable for small size of sample.

Finally, future research in this area will extend more complicated problems in which other probability models, inspection schemes and censoring types as type—II or progressively will be considered.

Also, because optimal plan is less robust to deviations from assumed model (see Meeker (1984) and Meeker and Hahn (1985)), compromise accelerated life test plans with subexperiments more than two stress levels may be recommended.

REFERENCES

- Archer, N. P. (1982), "Maximum Likelihood Estimation with Weibull Models When Data are Grouped", Commun. Statist. - Theory and Meth., 11, 199-207.
- Burridge, J. (1980), "A Note on Maximum Likelihood Estimation for Regression Model Using Grouped Data", J. R. Statist, Soc, B, 43, 41-45.
- 3. Chernoff, H. (1962), "Optimum Accelerated Life Designs for Estimation", Technometrics, 4, 381-408.
- 4. Cheng, K.F. and Chen, C.H. (1988), "Estimation of the Weibull Parameters with Grouped Data", Commun. Statist.—
 Theory and Meth., 17, 325-341.
- Choi, Seung-Cheol (1987), Optimal Design of Accelerated Life Tests under Periodic Inspection, KAIST Unpublished Master Thesis.
- Ehrenfeld, S. (1962), "Some Experimental Design Problem in Attribute Life Testing", J. A. S. A., 57, 668-679.
- 7. Escobar, L.A. and Meeker, W.Q. (1986), "Elements of the Fisher Information Matrix for the Smallest Extreme Value Distribution and Censored Data", Applied Statist., 35, 80-86.
- 8. Hassanein, K.B. (1972), "Simultaneous Estimation of the Parameters of the Extreme Value Distribution by Sample Quantiles", Technometrics, 14, 63-72.
- Kulldorff, O. (1961), Estimation from Grouped and Partially Grouped Sample, Almqvist and Wiksell, Stockholm.
- Lawless, J. F. (1982), Statistical Models and Methods for Lifetime Data, Wiley, New York.

- 11. Lawless, J. F. (1983), "Statistical Methods in Reliability (with discussion)", Technometrics, 25, 305-335.
- 12. Little, R.E. and Jebe, M.H. (1969), "A Note on the Gain in Precision for Optimum Allocation in Regression as Applied to Extrapolation in S-N Fatigue Testing", Technometrics, 11, 389-392.
- 13. Mann, N.R. (1972), "Design of Over— Stress Life Test Experiments when Failure Times have the Two—Parametre Weibull Distribution", Technometrics, 14, 437— 451.
- 14. Mann, N.R., Schafer, R.E. and Singpurwalla, N.D. (1974), Methods for Statistical Analysis of Reliability and Life Data, Wiley, New York.
- 15. Meeker, W.Q. (1984), "A Comparision of Accelerated Life Test Plans for Weibull and Lognormal Distribution and Type-I Censoring", Technometrics, 26, 157-171.
- 16. Meeker, W.Q. (1986), "Planning Life Tests in Which Units are Inspected for Failure", IEEE Trans. Rel., 35, 571-578.
- 17. Meeker, W.Q. and Hahn, G.J. (1985), "How to Plan an Accelerated Life Test—Some Practical Guidelines", ASQC Basic References in Quality Control: Statistical Techniques, Vol. 10, Milwaukee.
- Meeker, W.Q. and Nelson, W. (1976),
 "Optimum Accelerated Life Test for Weibull and Extreme Value Distributions",
 IEEE Trans. Rel., 25, 20-24.
- Nelson, W. (1977), "Optimum Demonstration Tests with Grouped Inspection Data from an Exponential Distribution", IEEE Trans. Rel., 26, 226-231.

- 20. Nelson, W. and Keilpinski, T.J. (1975), "Optimum Censored Accelerated Life Tests for Normal and Lognormal Life Distributions", IEEE Trans. Rel., 24, 310-320.
- 21. Nelson, W. and Meeker, W.Q. (1978), "Theory for Optimum Censored Accelerated Life Tests for Weibull and Extreme Value Distribution", Technometrics, 20,

- 171 177.
- 22. Powell, M. J. D. (1964), "An Efficient Method for Finding the Minimum of a Function of Several Variables Without Calculating Derivatives", Computer J., 7, 155-162,
- 23. Rao, C.R. (1973), Linear Statistical Inference and Its Application, 2nd ed., Wiley, New York.